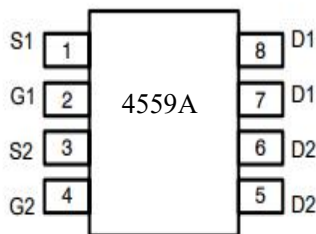
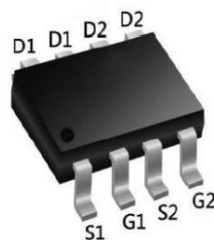


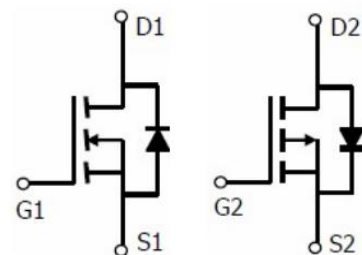
Features <ul style="list-style-type: none"> ➤ Super Low Gate Charge ➤ Green Device Available ➤ Excellent Cdv/dt effect decline ➤ Advanced high cell density Trench technology ➤ 100% EAS Guaranteed 	Bvdss	Rdson	ID
	60V	30mΩ	6A
	-60V	70mΩ	-5A
Application <ul style="list-style-type: none"> ➤ Power management in half bridge and in RoHS ➤ Load Switch ➤ DC-DC Converter 			

Package


Marking and pin assignment



SOP-8 top view



N-channel

P-channel

Schematic diagram

Package Marking and Ordering Information

Device Marking	Device	Device Package	Quantity
4559A	4559A	SOP-8	5000

Absolute Maximum Ratings

Parameter	Symbol	Value		Unit
		N-Channel	P-Channel	
Drain-Source Voltage	V_{DS}	60	-60	V
Gate-Source Voltage	V_{GS}	± 20	± 20	V
Continuous Drain Current	$I_D@T_A = 25^\circ\text{C}, V_{GS}@10\text{V}^1$	6	-5	A
	$I_D@T_A = 70^\circ\text{C}, V_{GS}@10\text{V}^1$	4	-3.5	A
Pulsed Drain Current ²	I_{DM}	11	-8.5	A
Single Pulsed Avalanche Energy ³	E_{AS}	22.5	35.3	mJ
Avalanche Current	I_{AS}	22.6	-26.6	A
Total Power Dissipation ⁴	$P_D@T_A = 25^\circ\text{C}$	2.5	2.5	W
Junction Temperature Range	T_J	-55~+150		°C
Storage Temperature Range	T_{STG}	-55~+150		°C



Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Thermal Resistance Junction-Case ¹	$R_{\theta JC}$	62.5	°C/W
Thermal Resistance Junction-Ambient ¹	$R_{\theta JA}$	85	°C/W

Ordering Information

Ordering Number	Package	Pin Assignment			Packing
Halogen Free		G	D	S	
HL4559A	SOP-8	2,4	5,6,7,8	1,3	Tape Reel

N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=-250\mu A$	60	-	-	V
Static Drain-Source On-Resistance ³	$R_{DS(ON)}$	$V_{GS}=10V, I_D=5A$	-	30	40	mΩ
		$V_{GS}=-4.5V, I_D=3A$	-	36	50	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu A$	1.0	1.6	2.5	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=60V, V_{GS}=0V$	-	-	1	μA
Gate to Body Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	±100	nA
Forward Transconductance ⁴	g_{fs}	$V_{DS}=5V, I_D=10A$	-	15.5	-	S
Total Gate Charge	Q_g	$V_{GS}=10V, V_{DS}=30V, I_D=2.5A$	-	20.3	-	nC
Gate-Source Charge	Q_{gs}		-	3.7	-	
Gate-Drain Charge	Q_{gd}		-	5.3	-	
Turn-On Delay Time	$T_{d(on)}$	$V_{GS}=10V, V_{DS}=30V, R_G=1.8\Omega, I_D=5A$	-	7.6	-	ns
Rise Time	T_r		-	20	-	
Turn-Off Delay Time	$T_{d(off)}$		-	15	-	
Fall Time	T_f		-	24	-	
Input Capacitance	C_{iss}	$V_{DS}=25V, V_{GS}=0V, f=1\text{MHz}$	-	1148	-	pF
Output Capacitance	C_{oss}		-	58.5	-	
Reverse Transfer Capacitance	C_{rss}		-	49.4	-	
Body Diode Reverse Recovery Time	t_{rr}	$I_F=-5A, dI_F/dt=100A/\mu s$	-	29	-	ns
Body Diode Reverse Recovery Charge	Q_{rr}		-	43	-	nC
Diode Forward Voltage	V_{SD}	$I_S=5A, V_{GS}=0V$	-	-	1.2	V
Continuous Source Current	I_S	-	-	-	6	A
Pulsed Drain to Source Diode Current	I_{SM}	-	-	-	20	A



Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition : $T_J=25^{\circ}\text{C}$, $V_{DD}=30\text{V}$, $V_G=10\text{V}$, $L=0.5\text{mH}$, $R_G=25\ \Omega$, $I_{AS}=8.7\text{A}$
3. Pulse Test: Pulse Width $\leq 300\ \mu\text{s}$, Duty Cycle $\leq 0.5\%$

P-Channel Electrical Characteristics ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0\text{V}$, $I_D=-250\ \mu\text{A}$	-60	-	-	V
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=-48\text{V}$, $V_{GS}=0\text{V}$, $T_J=25^{\circ}\text{C}$	-	-	1	μA
		$V_{DS}=-48\text{V}$, $V_{GS}=0\text{V}$, $T_J=55^{\circ}\text{C}$	-	-	5	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}$, $I_D=250\ \mu\text{A}$	-1.0	-	-2.5	V
Drain-Source On-State Resistance ⁴	$R_{DS(on)}$	$V_{GS}=-10\text{V}$, $I_D=-3.5\text{A}$	-	70	100	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}$, $I_D=-3.1\text{A}$	-	100	115	
Forward Transconductance	g_{fs}	$V_{DS}=-5\text{V}$, $I_D=-3\text{A}$	-	8.5	-	S
Input Capacitance	C_{iss}	$V_{DS} = -15\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$	-	1137	-	pF
Output Capacitance	C_{oss}		-	76	-	
Reverse Transfer Capacitance	C_{rss}		-	50	-	
Total Gate Charge (-4.5V)	Q_g	$V_{DS} = -48\text{V}$, $V_{GS} = -4.5\text{V}$, $I_D = -3\text{A}$	-	12.1	-	nC
Gate-Source Charge	Q_{gs}		-	2.2	-	
Gate-Drain Charge	Q_{gd}		-	6.3	-	
Turn-On Delay Time	$T_{d(on)}$	$V_{DD} = -15\text{V}$, $V_{GS} = -10\text{V}$, $R_G = 3.3\ \Omega$, $I_D = -1\text{A}$	-	9.2	-	ns
Rise Time	T_r		-	20.1	-	
Turn-Off Delay Time	$T_{d(off)}$		-	46.7	-	
Fall Time	T_f		-	9.4	-	
Diode Forward Voltage ²	V_{SD}	$I_S = -1\text{A}$, $V_{GS} = 0\text{V}$, $T_J=25^{\circ}\text{C}$	-	-	-1.2	V
Continuous Source Current ^{1,5}	I_S	$V_G=V_D=0\text{V}$, Force Current	-	-	-6	A

Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
2. The data tested by pulsed, pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$
3. The EAS data shows Max. rating. The test condition is $V_{DD}=-25\text{V}$, $V_{GS}=-10\text{V}$, $L=0.1\text{mH}$, $I_{AS}=-24\text{A}$
4. The power dissipation is limited by 150°C junction temperature
5. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

N-Channel Typical Characteristics

Fig.1 Typical Output Characteristics

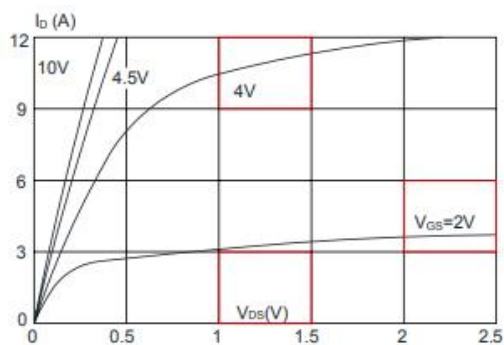


Fig.2 Typical Transfer Characteristics

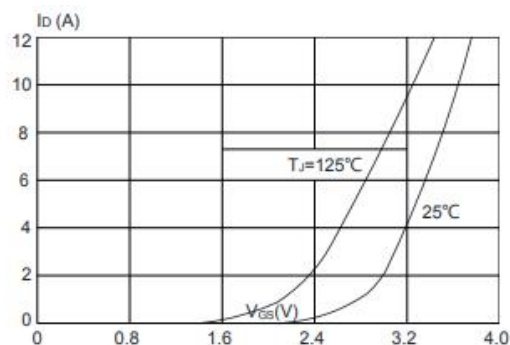


Fig.3 On-resistance vs. Drain Current

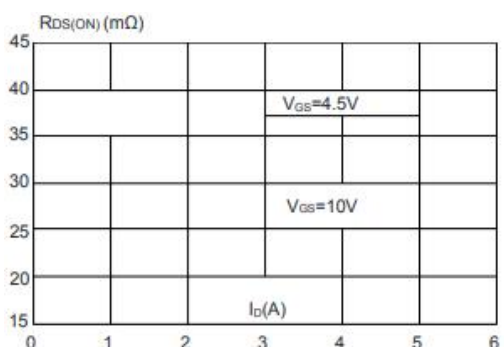


Fig.4 Body Diode Characteristics

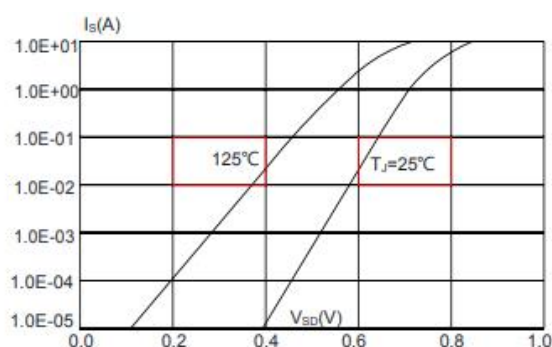


Fig.5 Gate Charge Characteristics

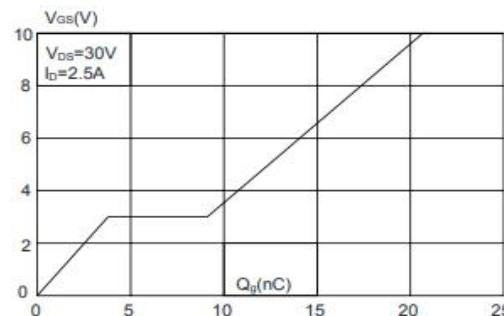


Fig.6 Capacitance Characteristics

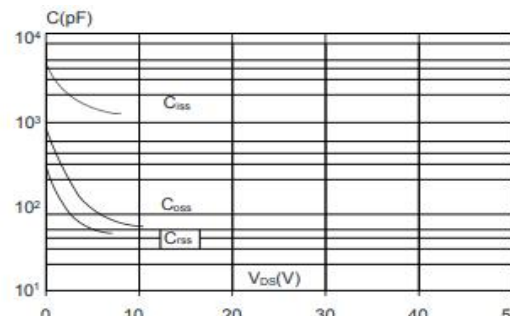


Fig.7 Normalized Breakdown Voltage vs. Junction Temperature

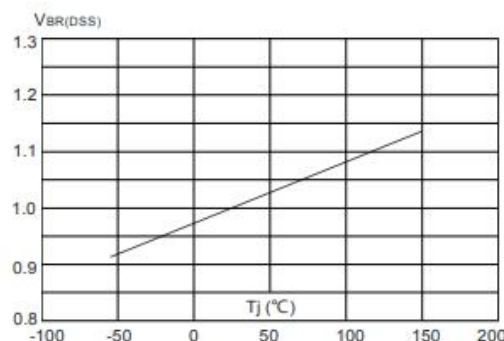


Fig.8 Normalized on Resistance vs. Junction Temperature

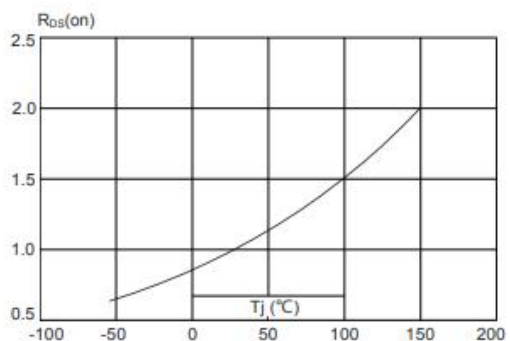


Fig.9 Maximum Safe Operating Area

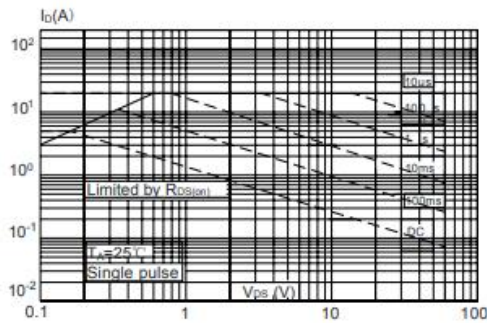


Fig.10 Maximum Continuous Drain Current vs. Ambient Temperature

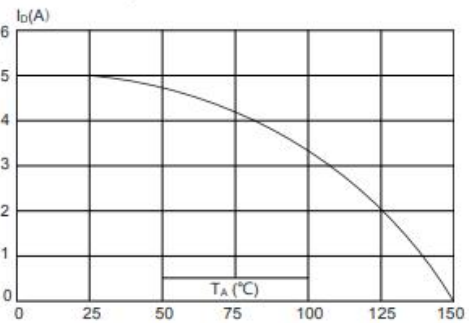
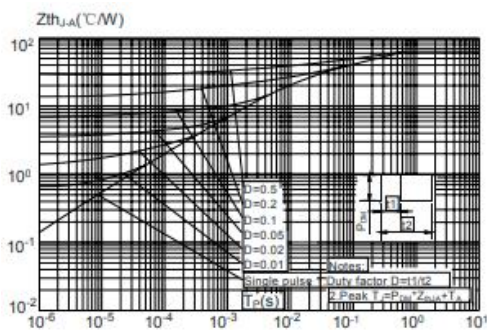


Fig.11 Normalized Maximum Transient Thermal Impedance



P-Channel Typical Characteristics

Fig.1 Typ. output characteristics

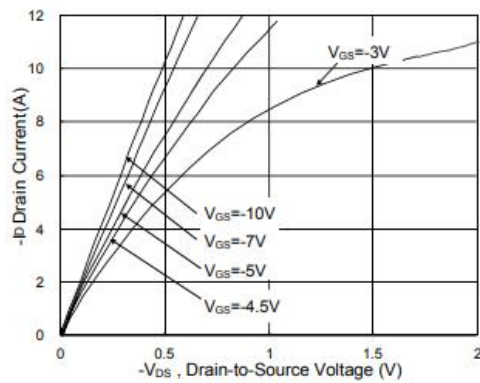


Fig.2 On-Resistance vs. G-S Voltage

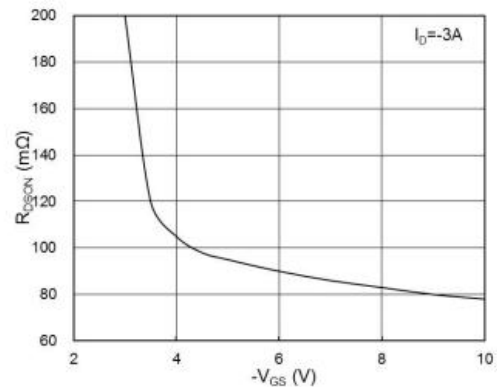


Fig.3 Source Drain Forward Characteristics

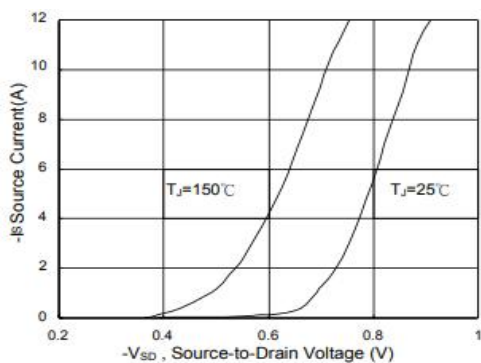


Fig.4 Gate-Charge Characteristics

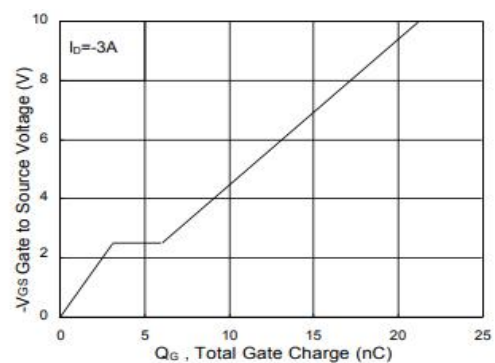


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

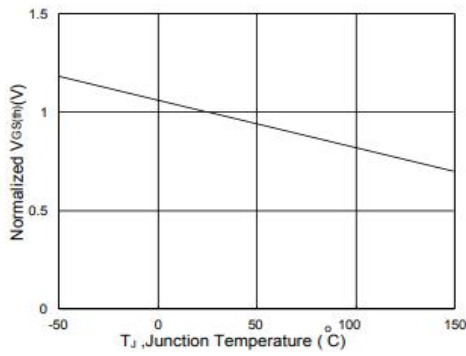


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

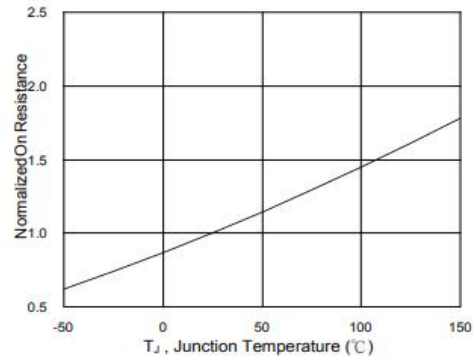


Fig.7 Capacitance

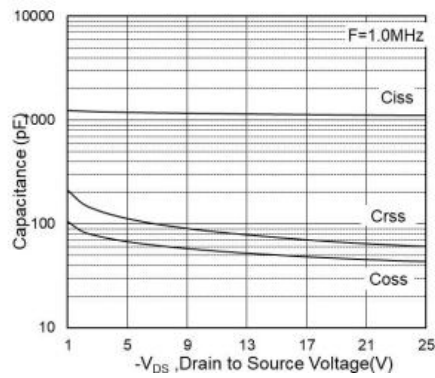


Fig.8 Safe Operating Area

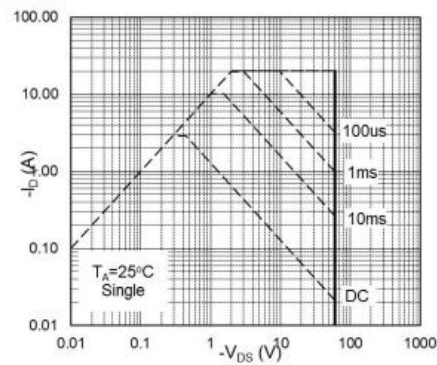


Fig.9 Normalized Maximum Transient Thermal Impedance

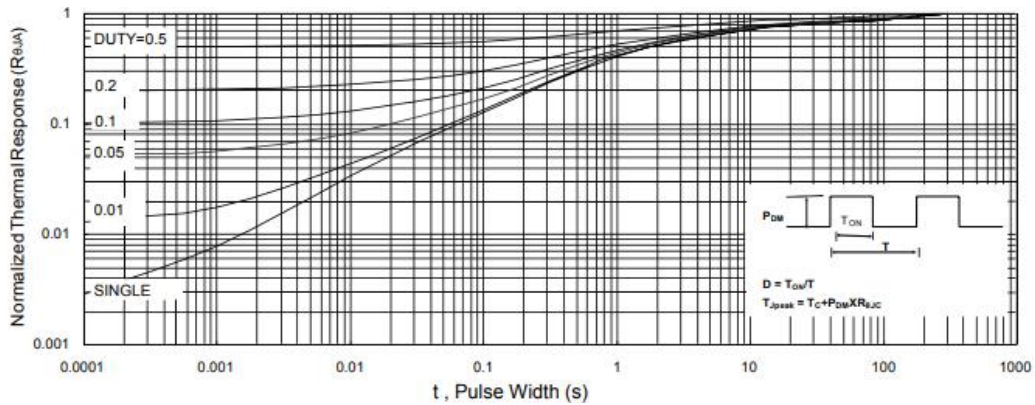


Fig.10 Switching Time Waveform

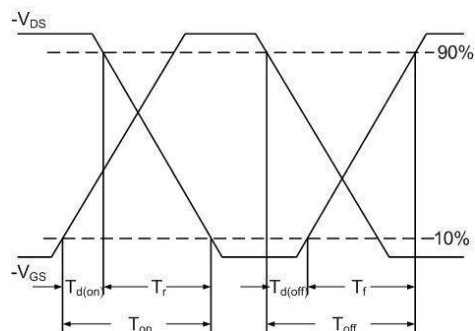
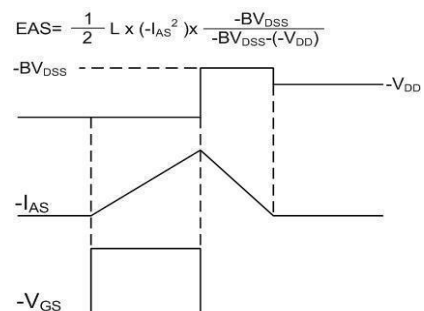
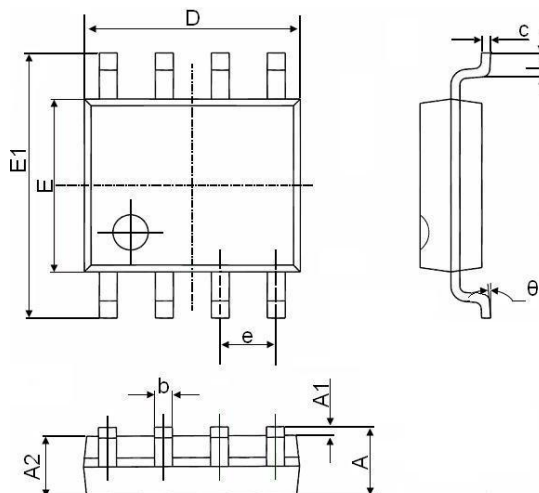


Fig.11 Unclamped Inductive Waveform



Package Dimensions SOP-8


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
b	0.330	0.510	0.013	0.020
c	0.170	0.250	0.006	0.010
D	4.700	5.100	0.185	0.200
E	3.800	4.000	0.150	0.157
E1	5.800	6.200	0.228	0.244
e	1.270(BSC)		0.050(BSC)	
L	0.400	1.270	0.016	0.050
theta	0°	8°	0°	8°



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